

Notice of References Cited	Application/Control No. 10/696,115		Applicant(s)/Patent Under Reexamination LOUI ET AL.	
	Examiner Nancy Bitar		Art Unit 2631	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,576,759	11-1996	Kawamura et al.	348/207.99
*	B	US-5,083,860	01-1992	Miyatake et al.	352/129
*	C	US-6,993,180	01-2006	Sun et al.	382/165
*	D	US-5,872,859	02-1999	Gur et al.	382/128
	E	US-			
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	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	EP 0990996 A2	04-2000	EP	Loui et al.	
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	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Hansen et al.(Models for Time Coalescence in Event Logs) ,Jeffery P. Hansen and Daniel P. Siewiorek, Department of Electric and Computer Engineering ,Carnegie Mellon University,Pittsburg,PA15213 USA
	V	XP-002140074,"Introduction to Statistical Pattern Recognition","Clustering"Chapter II ,Fukanage,pp.509-523
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.